

## **Supporting Information**

### **A Highly Bendable and Durable Transparent Electromagnetic Interference Shielding Film Prepared by Wet Sintering of Silver Nanowires**

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## **Supporting Information**

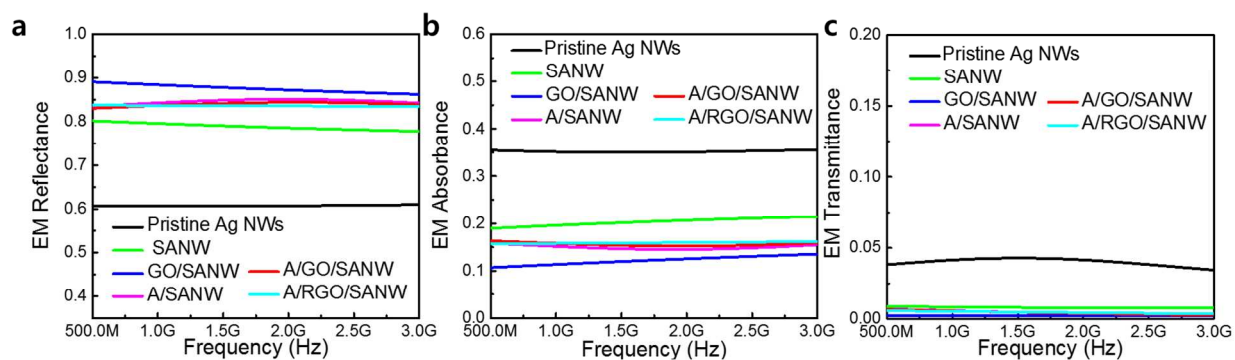
Figures S1, S2, and S3 provided in the Supporting Information document (.pdf file).

### **List of Supplementary Figures**

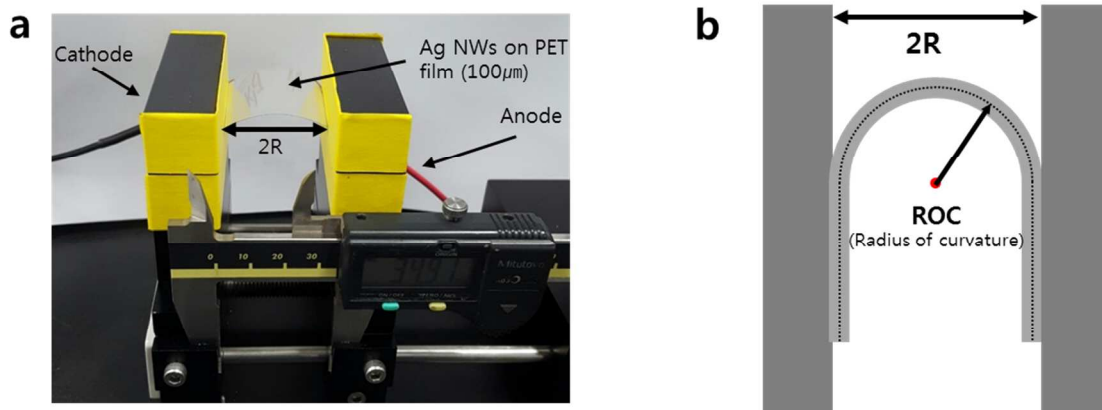
Supplementary **Figure S1**. Reflectance, absorbance, and transmittance of Ag NW EMI shielding films ( $T = 90.3\%$ ; at 550 nm).

Supplementary **Figure S2**. Image of the radius of curvature (ROC) bending tester; a schematic of ROC.

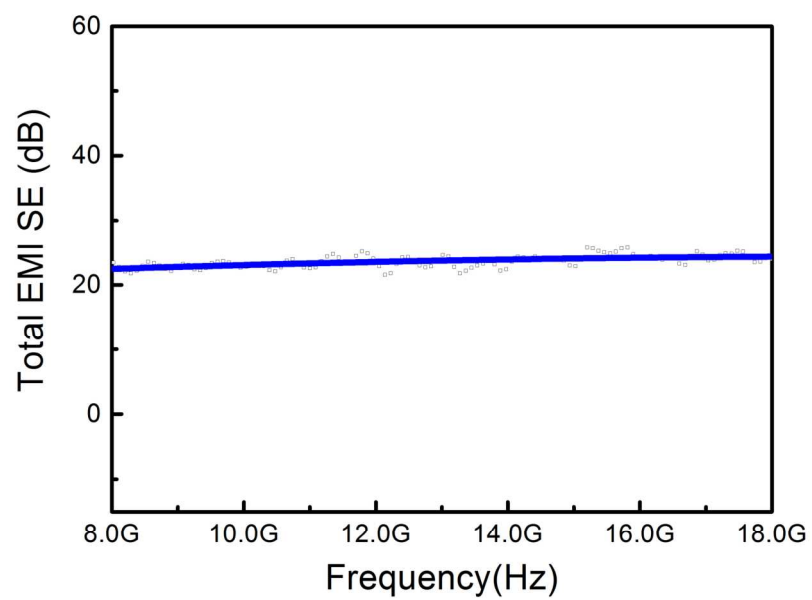
Supplementary **Figure S3**. Total EMI SE of A/RGO/SANW EMI shielding film at 8–18 GHz.



**Figure S1.** Reflectance, absorbance, and transmittance of Ag NW EMI shielding films ( $T = 90.3\%$ ; at 550 nm). (a) EM Reflectance, (b) EM absorbance, and (c) EM transmittance.



**Figure S2.** Image of the radius of curvature (ROC) bending tester (a); a schematic of ROC (b).



**Figure S3.** Total EMI SE of A/RGO/SANW EMI shielding film at 8–18 GHz.